

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/617,051	KOBAYASHI, FUMITOSHI	
Examiner		Art Unit		Page 1 of 1
Hae M Hyeon		2839		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,046,454	09-1977	Pugh, III, William Edward	385/59
	B	US-5,734,768	03-1998	Kim et al.	385/52
	C	US-2001/0055460 A1	12-2001	Steinberg, Dan A.	385/137
	D	US-2002/0131703 A1	09-2002	Velikov, Leonid	385/35
	E	US-6,731,853	05-2004	Boudreau et al.	385/137
	F	US-6,788,872	09-2004	Bonja, Jeffrey A.	385/137
	G	US-2004/0234226 A1	11-2004	Jeantilus et al.	385/137
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.